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2	3							
3	36							
4	81							
5	0							
6	143							
7	0							
8	4							
9	6							

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	X		US 20050027469 A1	20050203	12	De-embedding devices under test	702/117
2	X		US 20040031001 A1	20040212		MOSFET modeling for IC design accurate for high frequencies	716/4
3	X		US 20030132759 A1	20030717	12	Low loss integration of wafer probes with microwave tuners	324/601
4	X		US 20020024593 A1	20020228		3D scanning using shadows	348/46
5	X		US 6851097 B2	20050201		MOSFET modeling for IC design accurate for high frequencies	716/5
6	X		US 6618837 B1	20030909		MOSFET modeling for IC design accurate for high frequencies	716/4

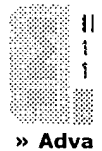
	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Brunsmann, Michael D.								US 20050027469	
2	703/14		Zhang, Xisheng et al.									
3			Tsironis, Christos								US 20030132759	
4	382/154		Bouquet, Jean-Yves et al.									
5	703/14; 703/2; 716/1; 716/4; 716/6		Zhang, Xisheng et al.									
6	703/14; 716/1		Zhang, Xisheng et al.									

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